

**Search Notes**

Application/Control No.

10/050,123

Examiner

Jason M. Perilla

Applicant(s)/Patent under  
Reexamination

YEN ET AL.

Art Unit

2638

**SEARCHED**

Class	Subclass	Date	Examiner
375	295	9/29/2005	JP
	146	9/29/2005	JP
	296	9/29/2005	JP
	297	9/29/2005	JP
710	8	9/29/2005	JP
375	316	2/16/2006	JP
	324	2/16/2006	JP
	325	2/16/2006	JP

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
375	316	2/16/2006	JP
	324	2/16/2006	JP
	325	2/16/2006	JP

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East USPAT/USPGPUB EPO/JPO	9/29/2005	JP
Inventor Name Search East/EDAN	9/29/2005	JP